

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

246239US2S

SERIAL NO.

10/728,928

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yoshinori KITAMURA, et al.

FILING DATE

December 8, 2003

GROUP

2814

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TD	AA	4,369,565	01/25/1983	Akira MURAMATSU			
TD	AB	6,720,610 B2	04/13/2004	Tadashi IGUCHI, et al.			
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

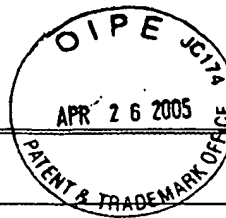
Examiner

Z/bran

Date Considered

7/22/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SHEET 1 OF 1

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TD	AA	6,768,161 B2	07/27/2004	Hideyuki KINOSHITA			
	AB						
	AC						
	AD						
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	AI						
	AJ						
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	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
TD	AO	11-317464	11/16/1999	JAPAN		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

TD	AW	Peter VanDerVoorn, et al., CMOS Shallow-Trench-Isolation to 50-nm Channel Widths*, IEEE Transactions on Electron Devices, vol. 47, no. 6, June 2000, pages 1175-1182				
	AX					
	AY					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Z. Ivan

Date Considered

7/22/05

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NEW APPLICATION

LIST OF REFERENCES CITED BY APPLICANT

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FILING DATE

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GROUP

2814

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TD	AA	5,949,101	09/07/99	Seichi ARITOME			
	AB						
	AC						
	AD						
	AE						
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	AH						
	AI						
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	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
TD	AO	2001-168306	06/22/01	Japan		X
TD	AP	7-254652	10/03/95	Japan		X
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

2/Noam

Date Considered

1/26/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.